

**Search Notes**

Application/Control No.

10/614,876

Examiner

Jeffrey J. Chow

Applicant(s)/Patent under  
Reexamination

CAO ET AL.

Art Unit

2672

**SEARCHED**

Class	Subclass	Date	Examiner
345	442, 420, 619	11/2/2005	JJC

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
"quadratic bezier" and flatness	11/2/2005	JJC
bezier and bisection	11/2/2005	JJC
Did an inventor search No double patenting	10/27/2005	JJC